



Edition 1.0 2021-10

TECHNICAL SPECIFICATION



Nanomanufacturing – Key control characteristics –
Part 9-1: Traceable spatially resolved nano-scale stray magnetic field measurements – Magnetic force microscopy





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IEC TS 62607-9-1

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

ICS 07.120 ISBN 978-2-8322-1032-9

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